

JOURNAL OF ELECTRONIC TESTING:
Theory and Applications
(JETTA)

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ELECTRONIC
TESTING
Theory and Applications (JETTA)

Editor in Chief: Vishwani Agrawal

Volume 40, Number 2, April 2024

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Volume 40, Number 2, April 2024 137 – 288

A journal serving electronic test professionals
in concurrence with the Test Technology Technical Council
(TTTC) of the IEEE Computer Society



Springer



ISSN: 0923-8174